

**Notice of References Cited**

Application/Control No.

10/589,994

Applicant(s)/Patent Under  
Reexamination  
SMITH ET AL.

Examiner

COLLEEN M. RAPHAEL

Art Unit

1724

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,536,885 A	10-1970	MITCHELL PETER	219/121.11
*	B	US-3,983,021 A	09-1976	Henis, Jay M.	204/164
*	C	US-5,418,430 A	05-1995	Bayliss, Keith H.	315/111.21
*	D	US-6,617,538 B1	09-2003	Mahawili, Imad	219/121.36
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kim et al, "Comparative Measurements on Thermal Plasma Jet Characteristics in Atmospheric and Low Pressure Plasma Spraysings," IEEE Transactions on Plasma Science, vol. 23, no. 5, October 1995, pp. 852-859
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.